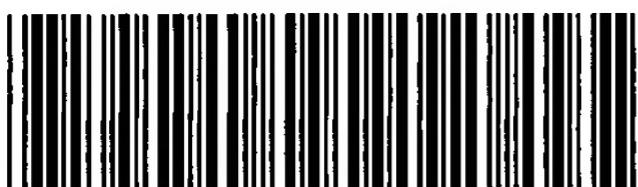


Search Notes



Application/Control No.

10/644,939

Examiner

Djenane M. Bayard

**Applicant(s)/Patent under
Reexamination**

CHEN, RICHARD C.

Art Unit

2141

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

INTERFERENCE SEARCHED

INTERFERENCE SEARCHED